

SUPPLEMENTARY MATERIAL:

The Anti-Reflection Coating Design for the Very-Long-Wave-Infrared Si-Based Blocked-Impurity-Band Detectors

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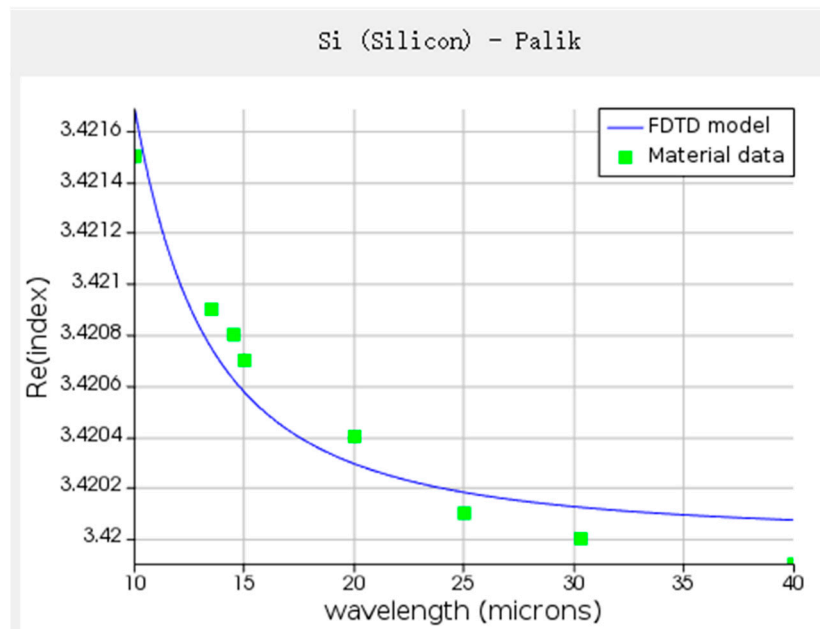


Figure S1. The refractive index of Si.

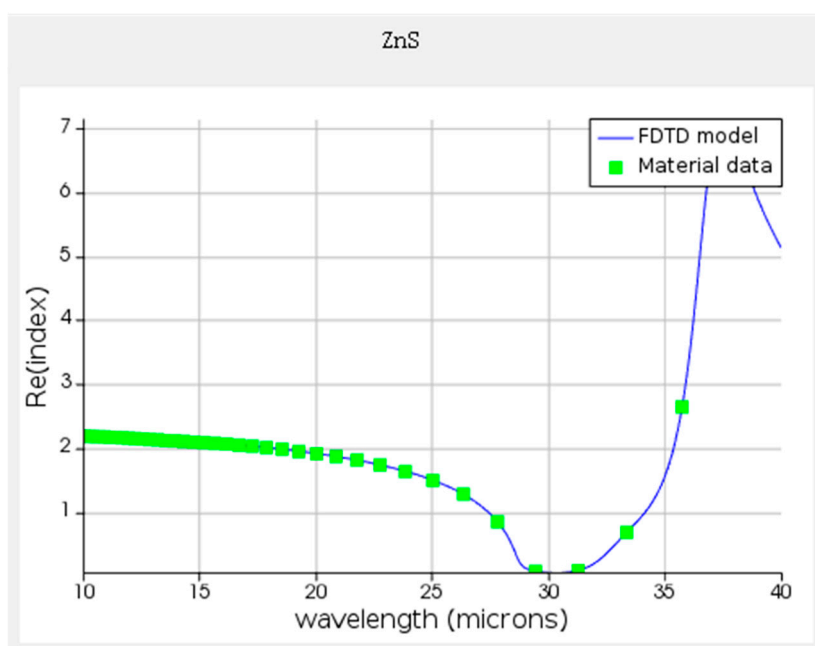


Figure S2. The refractive index of ZnS.